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INFORMATION DISCLOSURE	Complete if Known		
STATEMENT BY APPLICANT	Application Number	08/903453	
(Use as many sheets as necessary)	Filing Date	July 29, 1997	
OIPE	First Named Inventor	Forbes, Leonard	
(%)	Gr up Art Unit	2815	
SEP 2 6 2002 8	Examiner Name	Eckert II, George	
Sheet 1 of 1	Attorney Docket No: 0	0303.378US1	
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NOV 0 1 2002 1	First Named Inventor	Forbes, Leonard		
	Group Art Unit	2815		
	Examiner Name	Eckert II, George		
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